RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2117

PATENT APPLICATION
Docket No.: 4591-363
Client Ref. No.: IB13018-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:	Nam-Jung HER, et al.		
Confirmation No.:	5596		
Serial No.:	10/803,792	Examiner:	Radosevich, Steven D.
Filed:	March 17, 2004	Group Art Unit:	2138
For:	SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A NUMBER OF DATA OUTPUT PINS CAPABLE OF SELECTIVELY PROVIDING OUTPUT SIGNALS AND TEST METHOD THEREOF		

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL REJECTION

Responsive to the Final Office Action dated May 8, 2007, please amend the application as follows.

Claims begin on page 2.

Remarks begin on page 5.